INTEGRATED CIRCUITS



Product specification Supersedes data of 1995 Sep 06 IC23 Data Handbook

1998 Jan 16



74ABT244

FEATURES

- Octal bus interface
- 3-State buffers
- Output capability: +64mA/-32mA
- Latch-up protection exceeds 500mA per Jedec Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model
- Power-up 3-State
- Live insertion capacity
- Inputs are disabled during 3-State mode

QUICK REFERENCE DATA

DESCRIPTION

The 74ABT244 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

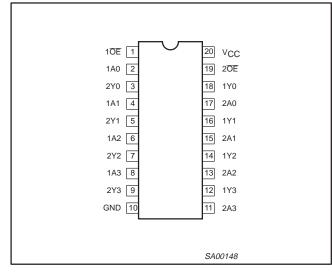
The 74ABT244 device is an octal buffer that is ideal for driving bus lines. The device features two Output Enables ($1\overline{OE}$, $2\overline{OE}$), each controlling four of the 3-State outputs.

SYMBOL	PARAMETER	CONDITIONS T _{amb} = 25°C; GND = 0V	TYPICAL	UNIT
t _{PLH} t _{PHL}	Propagation delay An to Yn	C _L = 50pF; V _{CC} = 5V	2.9	ns
C _{IN}	Input capacitance	$V_I = 0V \text{ or } V_{CC}$	4	pF
C _{OUT}	Output capacitance	Outputs disabled; $V_O = 0V$ or V_{CC}	7	pF
I _{CCZ}	Total supply current	Outputs disabled; V_{CC} =5.5V	50	μΑ

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
20-Pin Plastic DIP	–40°C to +85°C	74ABT244 N	74ABT244 N	SOT146-1
20-Pin plastic SO	–40°C to +85°C	74ABT244 D	74ABT244 D	SOT163-1
20-Pin Plastic SSOP Type II	–40°C to +85°C	74ABT244 DB	74ABT244 DB	SOT339-1
20-Pin Plastic TSSOP Type I	–40°C to +85°C	74ABT244 PW	74ABT244PW DH	SOT360-1

PIN CONFIGURATION

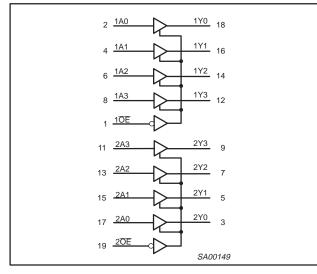


PIN DESCRIPTION

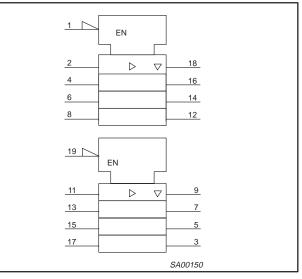
PIN NUMBER	SYMBOL	NAME AND FUNCTION			
2, 4, 6, 8	1A0 – 1A3	Data inputs			
11, 13, 15, 17	2A0 – 2A3	Data inputs			
18, 16, 14, 12	1Y0 – 1Y3	Data outputs			
9, 7, 5, 3	2Y0 – 2Y3	Data outputs			
1, 19	1 <u>0E</u> , 2 <u>0E</u>	Output enables			
10	GND	Ground (0V)			
20	V _{CC}	Positive supply voltage			

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LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



FUNCTION TABLE

	INP	OUTF	PUTS		
1 <mark>0E</mark>	1An	2 0E 2An		1Yn	2Yn
L	L	L	L	L	L
L	н	L	н	н	н
н	х	н	х	Z	Z

H = High voltage level

L = Low voltage level X = Don't care Z = High impedance "off" state

ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
I _{IK}	DC input diode current	V ₁ < 0	-18	mA
VI	DC input voltage ³		-1.2 to +7.0	V
I _{OK}	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	output in Off or High state	-0.5 to +5.5	V
I _{OUT}	DC output current	output in Low state	128	mA
T _{stg}	Storage temperature range		65 to 150	°C

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.

3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

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RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	ITS	UNIT
STWBOL	PARAMETER	Min	Max	UNIT
V _{CC}	DC supply voltage	4.5	5.5	V
VI	Input voltage	0	V _{CC}	V
V _{IH}	High-level input voltage	2.0		V
V _{IL}	Low-level Input voltage		0.8	V
I _{ОН}	High-level output current		-32	mA
I _{OL}	Low-level output current		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	5	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

DC ELECTRICAL CHARACTERISTICS

					LIMITS			
SYMBOL	PARAMETER	TEST CONDITIONS	Ta	_{mb} = +25	°C	T _{amb} =	: –40°C 85°C	UNIT
			Min	Тур	Max	Min	Max	
V _{IK}	Input clamp voltage	$V_{CC} = 4.5V; I_{IK} = -18mA$		-0.9	-1.2		-1.2	V
		V_{CC} = 4.5V; I_{OH} = -3mA; V_I = V_{IL} or V_{IH}	2.5	2.9		2.5		V
V _{OH}	High-level output voltage	V_{CC} = 5.0V; I_{OH} = -3mA; V_I = V_{IL} or V_{IH}	3.0	3.4		3.0		V
		V_{CC} = 4.5V; I_{OH} = -32mA; V_I = V_{IL} or V_{IH}	2.0	2.4		2.0		V
V _{OL}	Low-level output voltage	V_{CC} = 4.5V; I_{OL} = 64mA; V_I = V_{IL} or V_{IH}		0.42	0.55		0.55	V
l _l	Input leakage current	$V_{CC} = 5.5$ V; $V_I = GND$ or 5.5V		±0.01	±1.0		±1.0	μA
I _{OFF}	Power-off leakage current	V_{CC} = 0.0V; V_{O} or $V_{I}~\leq~4.5V$		±5.0	±100		±100	μA
I _{PU/PD}	Power-up/down 3-State output current ³	V_{CC} = 2.0V; V_O = 0.5V; V_I = GND or V_{CC} ; V _{OE} = Don't care		±5.0	±50		±50	μΑ
I _{OZH}	3-State output High current	V_{CC} = 5.5V; V_{O} = 2.7V; V_{I} = V_{IL} or V_{IH}		5.0	50		50	μΑ
I _{OZL}	3-State output Low current	V_{CC} = 5.5V; V_{O} = 0.5V; V_{I} = V_{IL} or V_{IH}		-5.0	-50		-50	μΑ
ICEX	Output HIgh leakage current	V_{CC} = 5.5V; V_{O} = 5.5V; V_{I} = GND or V_{CC}		5.0	50		50	μΑ
Ι _Ο	Short-circuit output current ¹	$V_{CC} = 5.5 V; V_{O} = 2.5 V$	-40	-100	-180	-40	-180	mA
I _{CCH}		V_{CC} = 5.5V; Outputs High, V_I = GND or V_{CC}		50	250		250	μΑ
I _{CCL}	Quiescent supply current	V_{CC} = 5.5V; Outputs Low, V_{I} = GND or V_{CC}		24	30		30	mA
I _{CCZ}		V_{CC} = 5.5V; Outputs 3-State; V _I = GND or V _{CC}		50	250		250	μA
		Outputs enabled, one data input at 3.4V, other inputs at V_{CC} or GND; $V_{CC} = 5.5V$		0.5	1.5		1.5	mA
ΔI_{CC}	Additional supply current per input pin ²	Outputs 3-State, one data input at 3.4V, other inputs at V _{CC} or GND; V _{CC} = 5.5V		50	250		250	μΑ
		Outputs 3-State, one enable input at 3.4V, other inputs at V_{CC} or GND; V_{CC} = 5.5V		0.5	1.5		1.5	mA

NOTES:

Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
This is the increase in supply current for each input at 3.4V.
This parameter is valid for any V_{CC} between 0V and 2.1V with a transition time of up to 10msec. For V_{CC} = 2.1V to V_{CC} = 5V ± 10%, a transition time of up to 100µsec is permitted.

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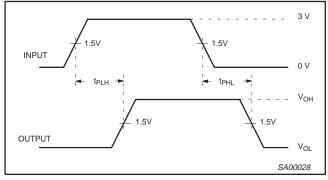
AC CHARACTERISTICS

GND = 0V; $t_R = t_F = 2.5 \text{ns}$; $C_L = 50 \text{pF}$, $R_L = 500 \Omega$

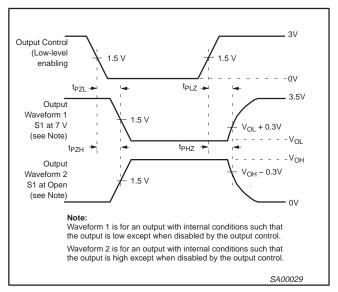
SYMBOL	PARAMETER	WAVEFORM	T _a V	_{imb} = +25° _{CC} = +5.0	C V	$T_{amb} = -40^{\circ}$ $V_{CC} = +5.$	UNIT	
			Min	Тур	Мах	Min	Max	
t _{PLH} t _{PHL}	Propagation delay An to Yn	1	1.0 1.0	2.6 2.9	4.1 4.2	1.0 1.0	4.6 4.6	ns
t _{PZH} t _{PZL}	Output enable time to High and Low level	2	1.1 2.1	3.1 4.1	4.6 5.6	1.1 2.1	5.1 6.1	ns
t _{PHZ} t _{PLZ}	Output disable time from High and Low level	2	2.1 1.7	4.1 2.7	5.6 5.2	2.1 1.7	6.6 5.7	ns

AC WAVEFORMS

 V_{M} = 1.5V, V_{IN} = GND to 3.0V



Waveform 1. Waveforms Showing the Input (An) to Output (Yn) Propagation Delays



Waveform 2. Waveforms Showing the 3-State Output Enable and Disable Times

7 V 500 Ω S1 .0 From Output Open Under Test GND 500 Ω $C_L = 50 \text{ pF}$ Load Circuit TEST **S**1 t_{pd} open 7 V t_{PLZ}/t_{PZL} t_{PHZ}/t_{PZH} open DEFINITIONS Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value. $C_L =$ SA00012

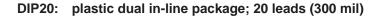
TEST CIRCUIT AND WAVEFORMS

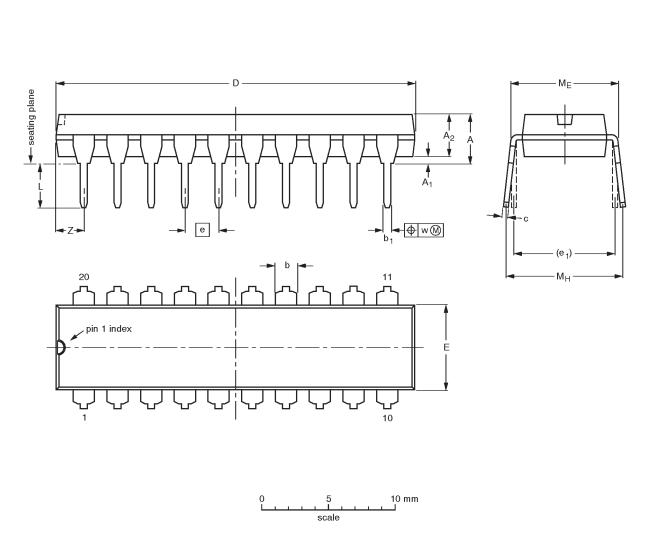
Product specification

SOT146-1

Octal buffer/line driver (3-State)

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DIMENSIONS (inch dimensions are derived from the original mm dimensions)

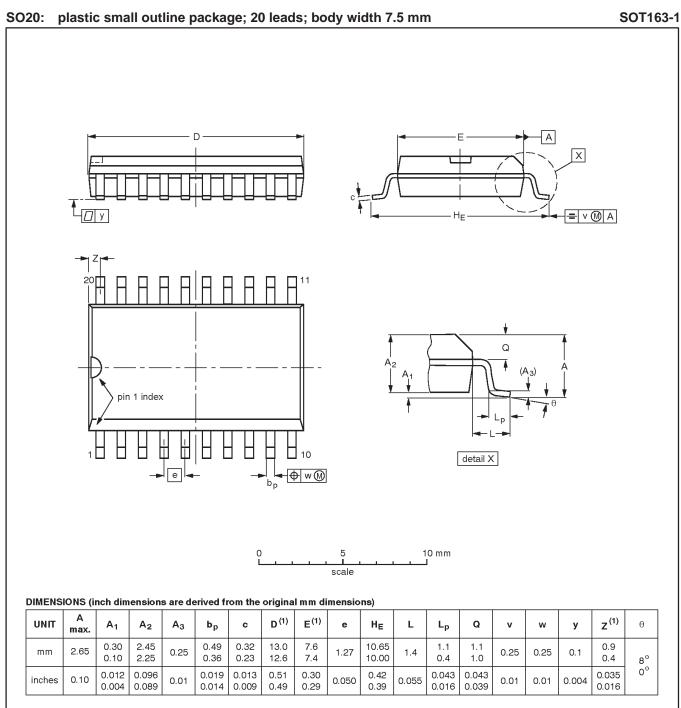
UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	c	D ⁽¹⁾	E ⁽¹⁾	e	e ₁	L	M _E	M _H	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	0.36 0.23	26.92 26.54	6.40 6.22	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.0
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.014 0.009	1.060 1.045	0.25 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.078

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

ſ	OUTLINE		REFER	RENCES	EUROPEAN	ISSUE DATE	
	VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE	
	SOT146-1			SC603		-92-11-17 95-05-24	

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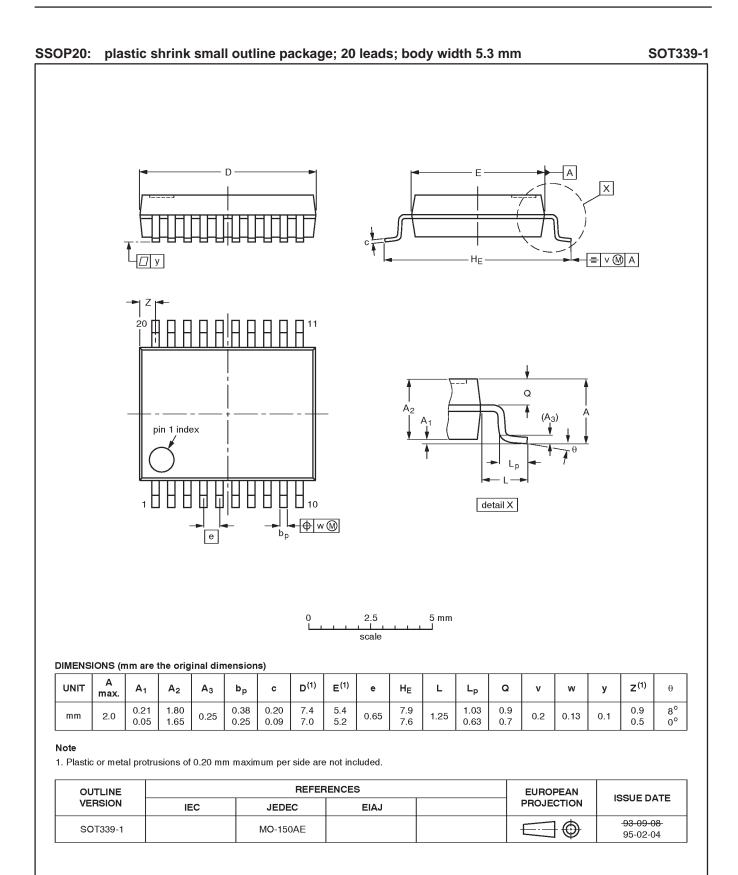


Note

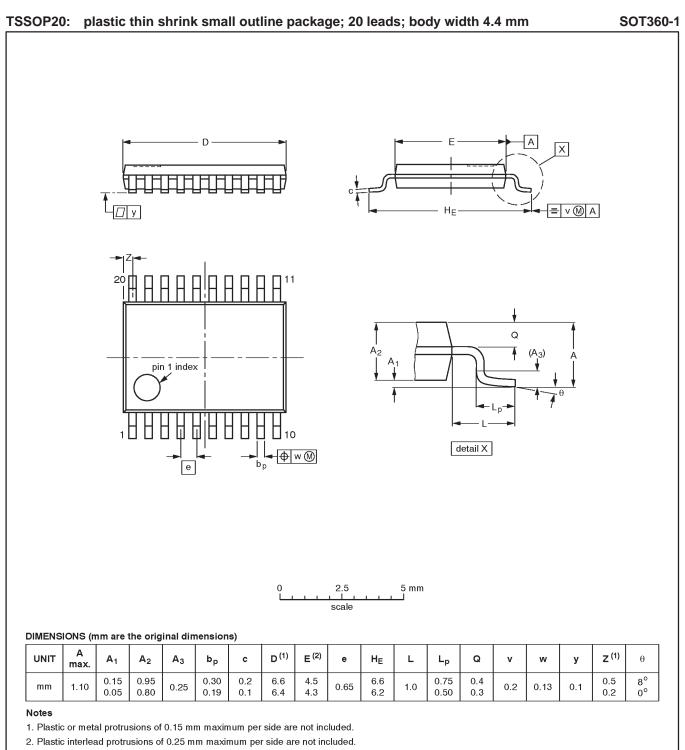
1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	RENCES	EUROPEAN ISSUE DAT		
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE	
SOT163-1	075E04	MS-013AC			-92-11-17 95-01-24	

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OUTLINE		REFER	ENCES	EUROPEAN		
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE	
SOT360-1		MO-153AC			-93-06-16 95-02-04	

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Data sheet status

Data sheet status	Product status	Definition ^[1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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